eGaN® FET DATASHEET EPC2040

EPC2040 – Enhancement Mode Power Transistor

 V_{DS} , 15 V $\overline{R_{DS(on)}}$, 30 m Ω I_D , 3.4 A









Revised April 23, 2021

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low R_{DS(on)}, while its lateral device structure and majority carrier diode provide exceptionally low $\mathbf{Q}_{\mathbf{G}}$ and zero $\mathbf{Q}_{\mathbf{RR}}$. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.



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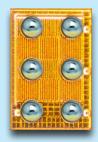
	Maximum Ratings			
	PARAMETER	VALUE	UNIT	
V	Drain-to-Source Voltage (Continuous)	15	V	
V _{DS}	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	18	V	
	$I_{D} = \frac{\text{Continuous} (T_{A} = 25^{\circ}\text{C}, R_{\theta JA} = 220^{\circ}\text{C/W})}{\text{Pulsed} (25^{\circ}\text{C}, T_{PULSE} = 300 \ \mu\text{s})}$		Α	
I _D			A	
V	Gate-to-Source Voltage 6		V	
V _{GS}	Gate-to-Source Voltage	-4	V	
T _J	T _J Operating Temperature		°C	
T _{STG}	Storage Temperature	-40 to 150	C	

	Thermal Characteristics			
	PARAMETER	ТҮР	UNIT	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	5.7		
R _{OJB} Thermal Resistance, Junction-to-Board 39 °C		°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	97		

Note 1: $R_{\theta JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.

	Static Characteristics (T _J = 25°C unless otherwise stated)					
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
BV _{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 300 \mu\text{A}$	15			٧
I _{DSS}	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 12 \text{ V}$		10	250	μΑ
	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		0.1	1.2	mΑ
I _{GSS}	Gate-to-Source Reverse Leakage	V _{GS} = -4 V		10	250	μΑ
V _{GS(TH)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	0.8	1.4	2.5	٧
R _{DS(on)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, } I_{D} = 1.5 \text{ A}$		24	30	mΩ
V _{SD}	Source-Drain Forward Voltage#	$V_{GS} = 0 \text{ V, } I_{S} = 0.5 \text{ A}$		2.2		٧

Defined by design. Not subject to production test. All measurements were done with substrate connected to source.



Die size: 0.85 x 1.2 mm

EPC2040 eGaN® FETs are supplied only in passivated die form with solder bumps.

Applications

- High speed DC-DC conversion
- · Lidar/pulsed power applications
- Lidar for augmented reality applications

Benefits

- · Ultra high efficiency
- Ultra low R_{DS(on)}
- Ultra low Q_G
- · Ultra small footprint

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



https://l.ead.me/EPC2040

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Dynamic Characteristics # (T _j = 25°C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
C _{ISS}	Input Capacitance			86	105	
C _{RSS}	Reverse Transfer Capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 6 \text{ V}$		20]
C _{OSS}	Output Capacitance			67	100	pF
C _{OSS(ER)}	Effective Output Capacitance, Energy Related (Note 2)	V 0VV 0+06V		106		
C _{OSS(TR)}	Effective Output Capacitance, Time Related (Note 3)	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ to } 6 \text{ V}$		87		
R_{G}	Gate Resistance			0.5		Ω
Q_{G}	Total Gate Charge	$V_{GS} = 5 \text{ V}, \ V_{DS} = 6 \text{ V}, \ I_D = 1.5 \text{ A}$		745	925	
Q _{GS}	Gate-to-Source Charge			230		
Q_{GD}	Gate-to-Drain Charge	$V_{DS} = 6 \text{ V}, I_{D} = 1.5 \text{ A}$		140]
Q _{G(TH)}	Gate Charge at Threshold			165		pC
Q _{OSS}	Output Charge	$V_{GS} = 0 \text{ V}, V_{DS} = 6 \text{ V}$		420	630]
Q _{RR}	Source-Drain Recovery Charge			0		

[#] Defined by design. Not subject to production test.

Figure 1: Typical Output Characteristics at 25°C

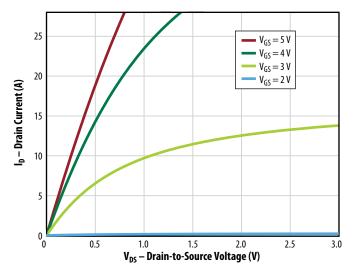


Figure 3: Typical $R_{\text{DS(on)}}\,\text{vs.}\,V_{\text{GS}}$ for Various Drain Currents

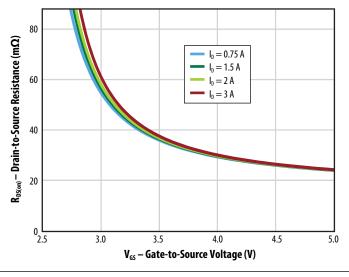


Figure 2: Typical Transfer Characteristics

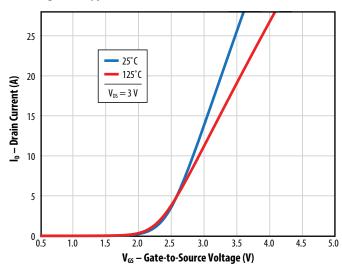
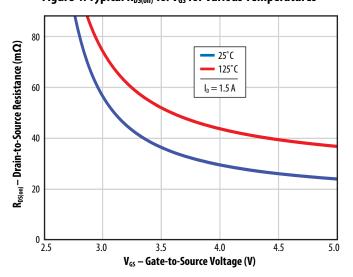


Figure 4: Typical R_{DS(on)} vs. V_{GS} for Various Temperatures



All measurements were done with substrate connected to source.

Note 2: $C_{OSS(ER)}$ is a fixed capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0 to 40% BV_{DSS} . Note 3: $C_{OSS(TR)}$ is a fixed capacitance that gives the same charging time as C_{OSS} while V_{DS} is rising from 0 to 40% BV_{DSS} .

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Figure 5a: Typical Capacitance (Linear Scale)

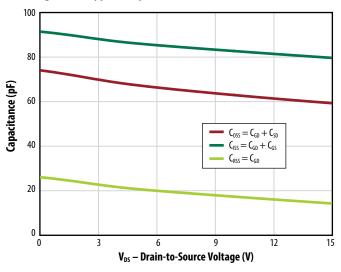


Figure 6: Typical Gate Charge

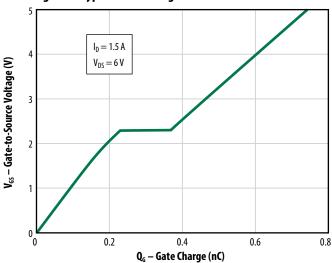


Figure 8: Typical Normalized On-State Resistance vs. Temp.

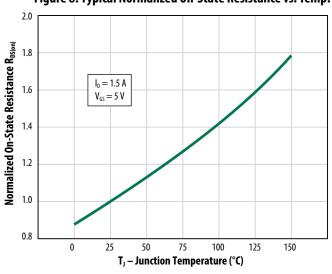


Figure 5b: Typical Capacitance (Log Scale)

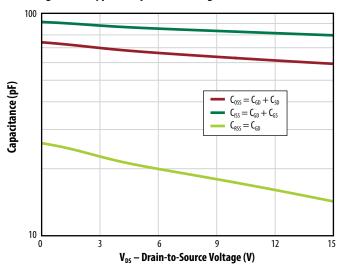
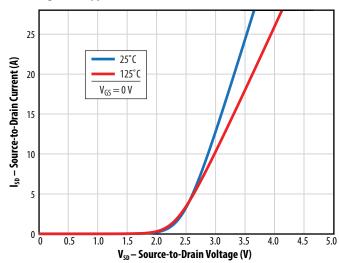
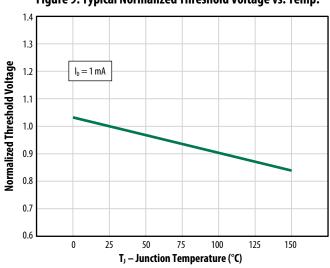


Figure 7: Typical Reverse Drain-Source Characteristics



Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

Figure 9: Typical Normalized Threshold Voltage vs. Temp.



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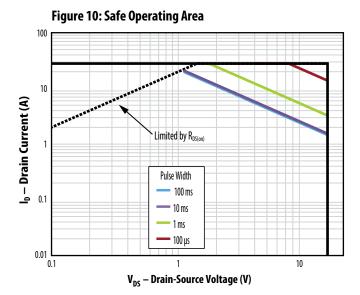
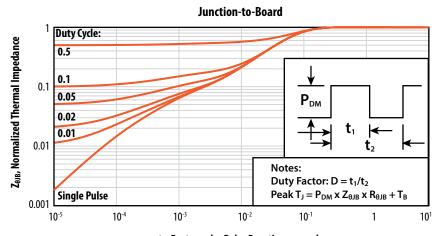
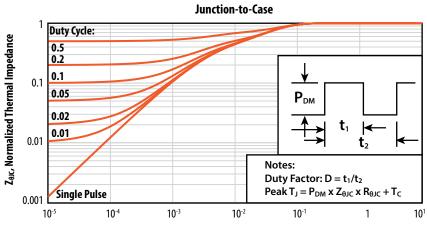


Figure 11: Typical Transient Thermal Response Curves



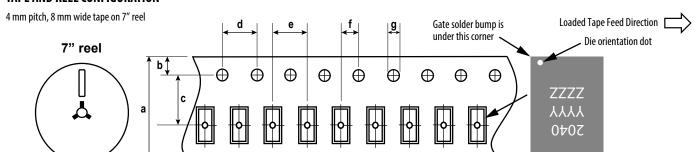
t₁, Rectangular Pulse Duration, seconds



t₁, Rectangular Pulse Duration, seconds

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TAPE AND REEL CONFIGURATION



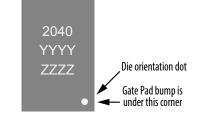
Die is placed into pocket
solder bump side down
(face side down)

	EPC2040 (note 1)		
Dimension (mm)	target	min	max
а	8.00	7.90	8.30
b	1.75	1.65	1.85
c (note 2)	3.50	3.45	3.55
d	4.00	3.90	4.10
е	4.00	3.90	4.10
f (note 2)	2.00	1.95	2.05
g	1.5	1.5	1.6

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard. Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

DIE MARKINGS

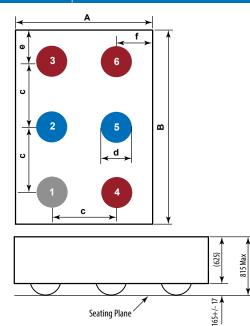
Part	Laser Markings			
Number	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking line 3	
EPC2040	2040	YYYY	ZZZZ	



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DIE OUTLINE

Solder Bump View



	Micrometers			
DIM	MIN	Nominal	MAX	
A	820	850	880	
В	1170	1200	1230	
c		400		
d	187	208	229	
e	185	200	215	
f	210	225	240	

Pad 1 is Gate;

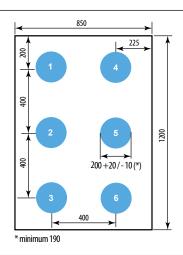
Pads 2, 5 are Drain;

Pads 3, 4, 6 are Source

RECOMMENDED LAND PATTERN

Side View

(measurements in μ m)



Solder mask opening

200 μm

The land pattern is solder mask defined.

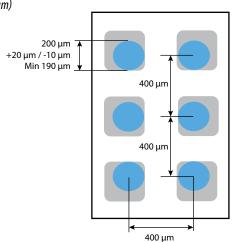
Pad 1 is Gate;

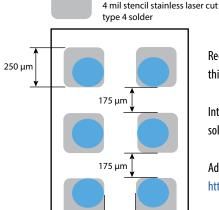
Pads 2, 5 are Drain;

Pads 3, 4, 6 are Source

RECOMMENDED STENCIL DRAWING

(measurements in μ m)





200 μm

Stencil opening

250 μm rounded square (60 deg)

Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, openings per drawing.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at https://epc-co.com/epc/design-support

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